

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/578,676	TANEYA ET AL.	
Examiner		Art Unit		Page 1 of 1
MARCOS BATISTA		4134		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,947,619 A	09-1999	Kurashina et al.	400/615.2
*	B	US-2004/0023685 A1	02-2004	Nakamura, Tamaki	455/550.1
*	C	US-2004/0058715 A1	03-2004	Taniguchi et al.	455/566
*	D	US-2004/0116167 A1	06-2004	Okuzako et al.	455/575.3
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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